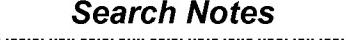


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/501,928	HIRAI ET AL.	
Examiner	Art Unit		
EDMUND H. LEE	1791		

Search Notes



Application/Control No.

10/501,928

Examiner

EDMUND H. LEE

**Applicant(s)/Patent under
Reexamination**

HIRAI ET AL.

Art Unit

1791

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)